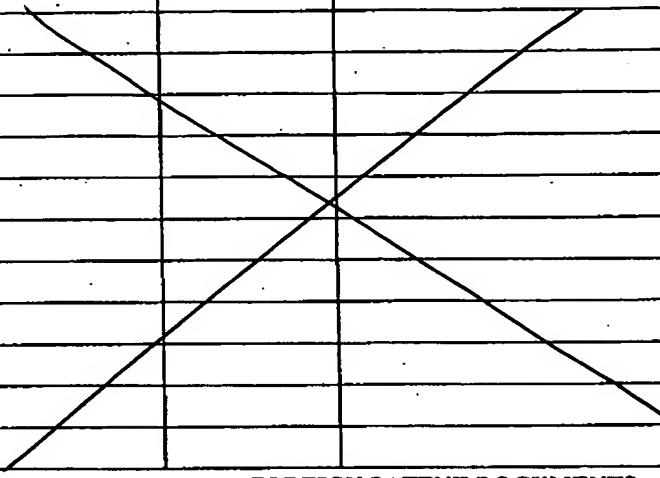
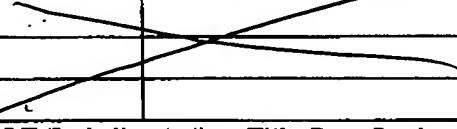
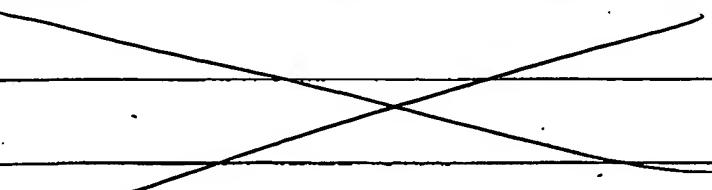


**BEST AVAILABLE COPY**

Sheet 1 of 1

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b> (PTO-1449)				ATTY. DOCKET NO. GAS-002	U.S. PATENT APPLICATION NO. 10/517,436	
				APPLICANT Jurgen Schulein et al		
				FILING DATE 02/10/2005	GROUP	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
Clm	US 5,830,343	11/03/1998	Rainer Hintsche et al	205	775	03/11/1996
						
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
Clm	DE 41 36 779 A1	05/13/1993	Germany	—	—	X
Clm	DE 100 15 818 A1	10/18/2001	Germany	—	—	X
						
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
						

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

**INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION**

(PTO-1449)

ATTY. DOCKET NO.  
GAS-002

**U.S. APPLICATION NO.**  
**Not yet assigned**

**APPLICANT:**  
Jurgen SCHULEIN et al.

FILING DATE herewith	GROUP
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# U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
an	4,655,880	04/07/1987	Liu			08/01/1983
an	2001/0029048	10/11/2001	Ding et al			03/12/1999
an	5,149,629	09/22/1992	Rishpon et al			04/04/1988
an	4,315,753	02/16/1982	Bruckenstein et al			08/14/1980
an	5,217,112	06/08/1993	Almon			09/04/1991

## FOREIGN PATENT DOCUMENTS

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

## **EXAMINER**

Abb. Noeggerath

**DATE CONSIDERED**

7/21/05

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.